

April 20, 2005

UPCOMING WEB SEMINARS – MAY & JUNE 2005

Vectorless PCB Test Workshop – Includes New FrameScan™ FX Overview

On Tuesday, April 26, 2005 at 9:00 a.m. and 3:00 p.m. (EDT, GMT-4), Teradyne will host a web-based workshop to examine advanced PCB vectorless test techniques that more accurately detect open pins on component packages and connectors. Register today for this in-depth look at the most advanced tool for testing open pins on an un-powered printed circuit board. Receive a first-hand overview of FrameScan FX, proven to be reliable and fast to implement. Learn how to take your vectorless test capabilities to a new level of accurate pin diagnostics and defect coverage.

Register at <https://teradyne-atd-events.webex.com>. For additional FrameScan information, go to: <http://www.teradyne.com/ict/teststation-in-circuit-test/framescan.html>

Low-Voltage PCB Test Workshop – Includes SafeTest™ Protocol Updates

On Wednesday, May 4, 2005 at 9:00 a.m. and 3:00 p.m. (EDT, GMT-4), Teradyne will host a web-based workshop to unveil new techniques for low-voltage PCB testing. Curriculum includes successful strategies, useful application hints and development advice for testing low-power, low-voltage PCBs. Real-world applications using Teradyne's SafeTest technology will be demonstrated.

Register at <https://teradyne-atd-events.webex.com>. For additional SafeTest information, go to <http://www.teradyne.com/ict/teststation-in-circuit-test/safetest.html>

AXI Versus AOI Roundtable – Trends & Issues

On Wednesday, May 18, 2005 at 9:00 a.m. and 3:00 p.m. (EDT, GMT-4), Teradyne will host a web-based AXI (X-Ray) versus AOI (Optical Inspection) roundtable to discuss the many trends and implementation issues surrounding visual and non-visual inspection techniques. Register today to gain valuable insight, as BGAs and chip-scale components challenge your next-generation inspection skills.

Register at <https://teradyne-atd-events.webex.com>. For additional AXI test information, go to <http://www.teradyne.com/axi/>

Boundary Scan – New Techniques and Application Practices

On Wednesday, June 15, 2005 at 9:00 a.m. and 3:00 p.m. (EDT, GMT-4), Teradyne will host a web-based forum to better understand new and significant boundary scan test methods. Attendees will receive helpful application advice and useful technology perspectives from the industry's leading PCB test system manufacturer.

Register at <https://teradyne-atd-events.webex.com>.

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